# Occupied and unoccupied surface states on the Si(111) $\sqrt{3} \times \sqrt{3}$ :B surface

T. M. Grehk

Materials Science, The Royal Institute of Technology, S-10044 Stockholm, Sweden

P. Mårtensson

Department of Physics and Measurement Technology, Linköping Institute of Technology, S-581 83 Linköping, Sweden

J. M. Nicholls\*

Materials Science, The Royal Institute of Technology, S-100 44 Stockholm, Sweden (Received 3 September 1991; revised manuscript received 10 April 1992)

The Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface has been studied with k-resolved inverse photoemission and angle-resolved photoemission. In the unoccupied region of the band structure, one strongly dispersing surface state is observed and in the occupied region, three surface states are observed. The unoccupied surface state is identified as an empty dangling-bond state and two of the occupied surface states are identified as backbond states of the adatom. The third occupied surface state, not observed on any other Si(111) $\sqrt{3} \times \sqrt{3}$ :group-III surfaces, is found to be connected with boron bonded beneath the surface top layer. The experimentally observed energy dispersions are compared with published band-structure calculations.

### **INTRODUCTION**

It is well established that  $\frac{1}{3}$  of a monolayer deposition of the group-III elements In, Ga, and Al onto a Si(111) surface can lead to a  $\sqrt{3} \times \sqrt{3}$  reconstruction.<sup>1-7</sup> By comparison between calculated and measured surfacestate dispersions it has been possible to determine the geometric structure of the surfaces, and it is shown that the three different group-III atoms occupy the  $T_4$  adatom position [see Fig. 1(a)], directly above a second-layer Si atom.<sup>2-6</sup> The lightest of the group-III elements, the B atom, distinguishes itself from the other elements by its ability to diffuse from the bulk of a Si sample towards the surface and when the concentration of B is high enough at the Si(111) surface a rearrangement of the  $7 \times 7$  reconstruction to the  $\sqrt{3} \times \sqrt{3}$  reconstruction can occur.<sup>8-12</sup>



FIG. 1. (a) The  $T_4$  adatom model with Si in the adatom position. (b) The B-S<sub>5</sub> adatom model where B is placed in a fivefold coordinated site directly under a Si adatom. (c) The  $\sqrt{3} \times \sqrt{3}$  SBZ relative to the  $1 \times 1$  SBZ.

Scanning tunneling microscopy (STM) measurements report that the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° structure is composed of Si adatoms on a Si double layer and that this configuration is stabilized by a high concentration of B in near-surface layers.<sup>9,10</sup> Total energy calculations of the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface predict that the B atom occupies the B-S<sub>5</sub> positioned [see Fig. 1(b)] in the second layer with a Si atom directly above it in the T<sub>4</sub> adatom position.<sup>9-11</sup>

In this work we present results from angle-resolved photoemission spectroscopy (ARPES) and k-resolved inverse photoemission spectroscopy (KRIPES) measurements on a Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface.

The surface reconstruction was obtained by annealing a heavily B-doped Si(111) wafer and was identified with low-energy electron diffraction (LEED). In contrast to ordinary bulk doped crystals, the samples used in the present study were doped by an implantation procedure, yielding a high B concentration ( $\geq 10^{20}$  cm<sup>-3</sup>) in the top 500 Å. Measurements were performed along the  $[10\overline{1}]$ ,  $[11\overline{2}]$ , and  $[2\overline{1}\overline{1}]$  symmetry directions. In the occupied region, two dispersing surface states with different intensity to  $k_{\parallel}$  relation and one surface state observable only around the  $\overline{\Gamma}'$  point in the second surface Brillouin zone (SBZ) were found. In the unoccupied region one strongly dispersing surface state was identified. All surface states showed a dispersion with the periodicity of the  $\sqrt{3} \times \sqrt{3}$ SBZ. A previously reported dispersion of an unoccupied surface state shows a maximum in energy position at the  $\overline{\Gamma}$  point<sup>11</sup> whereas a local minimum is observed in the data presented here. The measured data are compared with calculated dispersions for the geometries  $\operatorname{Si}(111)\sqrt{3} \times \sqrt{3}$ : SiR 30° with a Si in the  $T_4$  position and  $Si(111)\sqrt{3} \times \sqrt{3}$ : BR 30° with the B atom in the B-S<sub>5</sub> geometry.

#### **EXPERIMENT**

In the KRIPES experiment the surface is irradiated with a collimated beam of electrons from an electron gun, rotatable relative to the surface (with an angle resolution of  $\pm 1.5^{\circ}$  resulting in an uncertainty in momentum parallel to the surface of  $\Delta k_{\parallel} < 0.1 \text{ Å}^{-1}$ ). The emitted photons are collected by an elliptically shaped mirror and focused into a Geiger-Müller counter tube that filters and detects photons of energy hv=9.5 eV. The sample and mirror are mounted vertically and are held in fixed positions relative to each other, while the angle of incidence of the electrons is changed by rotating the electron gun in the horizontal plane via a goniometer. The combined energy resolution of the spectrometer, determined from the width of the Fermi level onset of a tantalum foil, is  $\Delta E = 0.35$  eV.

The ARPES experiments were performed with two different setups. In one setup, unpolarized light from a He resonance lamp (21.2 eV) was used. The emitted electrons were energy analyzed by a 180° hemispheric analyzer with a total energy and angle resolution of  $\leq 0.16$  eV and  $\pm 2^{\circ}$ . Measurements were also carried out using polarized synchrotron radiation (photon energies 15 and 21.2 eV) at MAXLAB synchrotron light source, Lund, Sweden. In the latter experiment the electrons were also energy analyzed with a 180° hemispherical analyzer and a total energy and angle resolution of 0.20 eV (15 eV), 0.18 eV (21.2 eV), and  $\pm 2^\circ$ , respectively, were used. Identification and azimuthal alignment of the surface were performed with LEED. In both the KRIPES and the ARPES studies the energy scale was referenced to the Fermi level of a tantalum foil, which was in electrical contact with the sample. The base pressure in all three vacuum chambers was  $\leq 2 \times 10^{-10}$  Torr. In the experiment using polarized synchrotron radiation, the electric field vector was always parallel to the probed crystal direction.

The sample was implanted with B ions of 90 keV energy to a coverage of  $5 \times 10^{15}$  cm<sup>-2</sup>. The sample was then oxidized in air. In ultrahigh vacuum the samples were thoroughly outgassed at 600 °C, and heated to 1050 °C in 1-min cycles. The sample temperature was measured with an infrared pyrometer. After 10 min of annealing a sharp  $\sqrt{3} \times \sqrt{3}$  LEED pattern had formed.

#### EXPERIMENTAL RESULTS

#### **Inverse photoemission**

Inverse photoemission spectra for the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface are displayed for the  $\overline{\Gamma}$ - $\overline{M}'$  direction in Fig. 2 and for the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$  direction in Fig. 3. The geometry of the  $\sqrt{3} \times \sqrt{3}$  SBZ relative to the  $1 \times 1$  SBZ is shown in Fig. 1(c). A dispersing state labeled U is identified at 1.15 eV above the Fermi level at the  $\overline{\Gamma}$  point. The total bandwidth of this state is 0.65 eV. The intensity of the U peak relative to the bulk related features was for short annealing times found to be proportional to the total time of heating. After ~10 min of annealing time no further improvement was observed in

the quality of the U state. A decrease in intensity of the U peak relative to the bulk related structure was observed when the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface was exposed overnight to rest gases of the vacuum chamber. The energy position of the peak U is in Fig. 4 plotted as a function of  $k_{\parallel}$ , together with the projected bulk band.<sup>13</sup> It is commonly known that the band gaps in band-structure calculations have a tendency to become too small.<sup>14</sup> Optical measurements on Si show an indirect band gap of 1.11 eV. Si has a conduction-band minimum along the  $\Gamma$ -X direction in the bulk Brillouin zone, which corresponds to the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$  direction in the  $\sqrt{3} \times \sqrt{3}$  SBZ when projected onto the Si(111) surface. The valence-band maximum is located at the  $\Gamma$  point. To compensate for the differences between measurements and calculations, the valence-band maximum and the conduction-band minimum of the projected bulk band structure from Ref. 13 have in Fig. 4 been separated to give a 1.11-eV band gap. This gives an energy difference at the  $\overline{\Gamma}$  point, between the projected valence-band maxima and the conduction-band minima, of 2.1 eV which is close to the value 2.4±0.15 eV observed in KRIPES measurements



FIG. 2. KRIPES spectra along the  $\overline{\Gamma}$ - $\overline{M}'$  azimuth. Tick marks denote the dispersing surface-state emission U.

on the Si(111)2×1 surface.<sup>14</sup> The value of the valenceband maximum  $E_{\rm VBM}$  relative to the Fermi level used in Fig. 4 is -0.5 eV.<sup>12</sup>

In the  $\overline{\Gamma}$ - $\overline{M}'$  direction the U state shows a symmetric dispersion around polar angles 27.5°-32.5°, that is, around the  $\overline{M}'$  point in the  $\sqrt{3} \times \sqrt{3}$  SBZ, with maxima in energy position of 1.35 eV at 12.5° and 52.5°. Local minima in energy position of 1.15 eV are observed at polar angles 0° and 62.5° corresponding to the  $\overline{\Gamma}$  and  $\overline{\Gamma}'$ point, respectively. In the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$  direction the U state reaches a maximum in energy position of 1.4 eV at polar angle 7.5° and a minimum of 0.75 eV at an angle of 32.5° corresponding to the  $\overline{K}'$  point in the  $\sqrt{3} \times \sqrt{3}$  SBZ. For higher angles of incidence a second maximum exists for polar angle between 47.5° and 52.5° corresponding to the region around the  $\overline{M}'$  point. In Fig. 4 the dispersion of U overlaps with the projected bulk at the  $\sqrt{3} \times \sqrt{3}$  zone border in the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$  direction. Accordingly in Fig. 3, spectra where the U state overlaps with the bulk bands, display a lower peak intensity than those where the Ustate is located in the band gap.

It can be seen in Fig. 4 that the U band is mainly positioned in the band gap of the projected bulk bands. Taking also into account that this state is not observed on the  $Si(111)7 \times 7$  surface<sup>15</sup> and its sensitivity to contamination, it can be concluded that the U state is a surface state.



FIG. 3. KRIPES spectra along the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$  azimuth. Tick marks denote the dispersing surface-state emission U.

The measured dispersion of the U peak in Fig. 4 is compared with calculated dispersions of the surfaces  $Si(111)\sqrt{3} \times \sqrt{3}$ :BR 30° with B in the B-S<sub>5</sub> position<sup>11</sup> and  $Si(111)\sqrt{3} \times \sqrt{3}$ :SiR 30° with the Si atoms in the T<sub>4</sub> geometry.<sup>16</sup>

It can be seen in Fig. 4 that the energy positions of the M' point in the  $\overline{\Gamma} \cdot \overline{K'} \cdot \overline{M'}$  direction and the  $\overline{\Gamma} \cdot \overline{M'}$  direction are the same. This indicates the existence of only one surface state in the unoccupied region.

In the KRIPES measurement on the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface performed by Kaxiras et al.<sup>11</sup> a surface-state dispersion is reported within the first  $\sqrt{3} \times \sqrt{3}$  zone with a maximum in energy position of  $\sim 1.3$  eV above the Fermi level at the  $\overline{\Gamma}$  point (see Fig. 4). It is reported that this surface state is dispersing towards lower-energy positions on both sides of the  $\overline{\Gamma}$  point to an energy position  $\sim 1$  eV at the  $\overline{M}'$  point in the  $\overline{\Gamma}$ - $\overline{M}'$  direction and to  $\sim 0.8$  eV at the  $\overline{K}'$  point in the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$  direction.

A comparison between the dispersion observed in Ref. 11 and the one presented here indicates a different energy position for the  $\overline{\Gamma}$  point [1.3 eV (Ref. 11) versus 1.15 eV]



FIG. 4. Plot of the surface-state dispersion for the directions  $\overline{\Gamma} \cdot \overline{M}'$  and the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$ . Included in the figure are calculated surface-state dispersions for the reconstructions  $\mathrm{Si}(111)\sqrt{3} \times \sqrt{.\mathrm{B}R} 30^\circ$  (Ref. 11) (-----) and  $\mathrm{Si}(111)\sqrt{3} \times \sqrt{3}$ :  $\mathrm{Si}R 30^\circ$  (Ref. 15) (-----). The dispersion labeled  $-\cdot - \cdot - \cdot$  is measured by Kaxiras *et al.* (Ref. 11). The shaded areas represent the projected bulk ( $E_F - E_{\mathrm{VBM}} = 0.5 \mathrm{~eV}$ ) (Ref. 14).

while similar energy positions are found for the  $\overline{M}'$  and  $\overline{K}'$  points. In Ref. 11 the reported dispersion has a maximum at the  $\overline{\Gamma}$  point whereas our measurements show a local minimum. These discrepancies could be an effect of different experimental setups but also of different sample preparation. In the measurement by Kaxiras *et al.*<sup>11</sup> the sample was a bulk doped Si wafer whereas in the present study a sample prepared by implantation of B into the surface region is used. The STM investigation by Bedrossian *et al.* on the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface<sup>10</sup> has shown that a sputter implantation of B into the surface region gives a surface which has a lower number of defects than if it is prepared from a bulk doped crystal.

# Angle-resolved photoemission

In Fig. 5 spectra recorded along the  $\Gamma \cdot \overline{M}'$  ([101]) and the  $\Gamma \cdot \overline{K}' \cdot \overline{M}'$  ([211]) directions with synchrotron radiation are shown ( $h\nu = 21.2$  eV). The directions  $\Gamma \cdot \overline{M}'$ ([101]) and  $\Gamma \cdot \overline{K}' \cdot \overline{M}'$ , along the two bulk inequivalent directions [112] and [211], were also studied using unpo-



FIG. 5. Photoemission spectra for various angles of emission  $\theta_e$ , at photon energy  $h\nu = 21.2$  eV, along the  $[10\overline{1}]$  and the  $[2\overline{1}\overline{1}]$  directions. Tick marks denote the identified surface-state peaks  $A_1$ ,  $A_3$ ,  $A'_3$ , and  $A_4$ .

larized He resonance light (hv=21.2 eV) and the direction  $\Gamma - \overline{M}'$  ([10]]) was studied with synchrotron radiation (hv=15 eV). Several surface related structures labeled  $A_1$ ,  $A_3$ ,  $A'_3$ , and  $A_4$  are present in the spectra as well as several bulk related peaks. The binding energies of the  $A_3$ ,  $A'_3$ , and  $A_4$  peaks are plotted in Fig. 4 as a function of  $k_{\parallel}$  for the directions  $\overline{\Gamma} - \overline{M}'$  and  $\overline{\Gamma} - \overline{K}' - \overline{M}'$ . The measured data in Fig. 4 are compared to calculated surface-state dispersions for the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° surface with Si in the  $T_4$  geometry.

The intensity of the  $A_3$  state is weak within the first  $\sqrt{3} \times \sqrt{3}$  SBZ ( $\theta_e \le 15^\circ$ ) in the probed symmetry directions but increases for the second SBZ. In the  $\overline{\Gamma}$ - $\overline{M}'$ direction the intensity has a maximum at  $\theta_e = 32.5^\circ$  corresponding to the  $\overline{\Gamma}'$  point and in the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$  direction a maximum in intensity is observed at  $\theta_e = 27.5^\circ$  corresponding to the  $\overline{M}'$  point. Spectra from measurements with polarized and unpolarized light show the same intensity behavior for the  $A_3$  and  $A'_3$  peaks. In the data for the unpolarized case, the peak  $A_4$  is weaker in intensity relative to the  $A_3$  peak, than in the polarized case. The dispersion of two states was the same in both experiments. The very weak structure  $A_1$  is visible close to the Fermi level at emission angles  $\leq 15^{\circ}$ , i.e., only within the first SBZ, shows no dispersion, and resembles the  $S_1$  peak observed on the Si(111)7 $\times$ 7 reconstruction.<sup>17</sup> The intensities of this peak were found to be dependent on the annealing time and in the experiment with unpolarized light it was found that after  $\frac{1}{2}$  hour of annealing the intensity of the peak was nearly zero. The intensity of the  $A_3$ ,  $A'_3$ , and  $A_4$  peaks was on the contrary found to be independent of annealing time. In STM measurement<sup>9,10</sup> on the Si(111):B surface a state near the Fermi energy in both the occupied and unoccupied region was found over "bright" atoms. The bright atoms are identified as Si adatoms in the  $T_4$  geometry (see Fig. 1). On the other hand, STM spectroscopy over dark atoms, identified as Si atoms with a B atom in the  $B_5$  position, showed no density of states in the vicinity of the Fermi level. The  $A_1$ feature, which shows no dispersion and is found to be dependent on annealing time, is therefore interpreted as a defect state of the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface arising from areas with Si adatoms in the  $T_4$  geometry.

By being positioned in the band gap of the projected bulk the bands  $A_3$ ,  $A'_3$ , and  $A_4$  are surface states. The dispersions along the  $\overline{\Gamma} \cdot \overline{M}'$  direction in Fig. 4 have different energy values at the  $\overline{M}'$  point  $E(\overline{M}') = -1.3$  eV  $(k_{\parallel} = 0.55 \text{ and } 1.16 \text{ Å}^{-1})$  than in the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$  direction  $E(\overline{M}') = -1.6$  eV  $(k_{\parallel} = 0.94 \text{ Å}^{-1})$ . The full width at half maximum of the peaks is 0.4 and 0.7 eV, respectively. The onset of the  $A_3$  and  $A'_3$  peaks relative to the Fermi level is the same in the spectra, -1.1 eV for the three  $\overline{M}'$ points. This indicates that  $A_3$  and  $A'_3$  contain two occupied bands with different intensity to  $k_{\parallel}$  relation. In Fig. 6, spectra recorded with unpolarized light at the  $\overline{\Gamma}'$  $(\theta_e = 27.5^\circ)$  point in the  $\overline{\Gamma} \cdot \overline{M}'$  direction of a clean surface, and one exposed to 250 L H<sub>2</sub> (1 L = 10<sup>-6</sup> Torr s) in the presence of a hot filament, are shown. The exposure led to a band bending of 0.3 eV towards lower binding energies measured with reference to the observed bulk



FIG. 6. ARUPS spectra of a clean and a H contaminated  $\sqrt{3}$ :B surface in the  $\overline{\Gamma}$ - $\overline{M}'$  direction at  $\theta_e = 27.5^\circ$ , corresponding to the  $\overline{M}'$  point.

features. In the figure the energy scale is referenced to the bulk features of the clean surface.

It has been shown that a saturation exposure of hydrogen on the Si(111)7 $\times$ 7 surface leads to a formation of silicon monohydride and the erasure of the three surface states at 0.2, 0.8, and 1.7 eV.<sup>18</sup> A comparison between the spectra obtained, at an emission angle off 30° in the  $\Gamma - \overline{M}'$ direction, from the clean Si(111)7  $\times$ 7 (Refs. 7 and 17) surface and the Si(111) monohydride surface,<sup>18</sup> displays in the monohydride case no observable bulk band structure, in the energy region down to 5 eV below the Fermi level. In the present study the exposure of 250 L of  $H_2$  to the  $Si(111)\sqrt{3} \times \sqrt{3}$ :BR 30° surface had no effect on the bulk related structure and only a minor effect on the  $A_4$  state whereas the intensity of the  $A_3$  structure was partially attenuated. Based on the distinction of the bulk feature of the hydrogen exposed Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface, in comparison to the washed out bulk feature of the Si(111)7 $\times$ 7 monohydride surface and that the A<sub>3</sub> surface state was only partially attenuated after the 250 L  $H_2$  exposure it can be assumed that the coverage on the  $Si(111)\sqrt{3} \times \sqrt{3}$ :BR 30° surface was in the submonolayer region. The decrease in intensity of the  $A_3$  peak reflects that this structure is connected to the bounding of the adatom to the first-layer atoms in a manner similar to that observed for the Si(111) $\sqrt{3} \times \sqrt{3}$ :AlR 30°, Ga, and In surfaces. The  $A_4$  peak, which is situated in the band gap, is not affected by the hydrogen exposure, and could correspond to the specific binding configuration below the surface caused by the position of the B atom in the  $B-S_5$ geometry.

## DISCUSSION

From first-principles pseudopotential total energy and electronic-structure calculations of the surfaces  $Si(111)\sqrt{3} \times \sqrt{3}$ :AlR 30°, Ga, In, and Si,<sup>2,3,6,16</sup> where the adatoms are positioned in the  $T_4$  position, one surface state is identified in the unoccupied region and two in the occupied region. The surface states in the unoccupied and occupied regions are related to the empty danglingbond and backbond states of the adatom. In general, the shapes of the calculated surface-state bands of the four surfaces resemble each other but they differ in bandwidth and absolute energy position. The calculated surface state of the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° in Fig. 4 can therefore exemplify the surface-state band structures of the other three surfaces, with the exception that the  $\Sigma_1$  band, which is half filled on the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° surface, is empty on the Si(111) $\sqrt{3} \times \sqrt{3}$ :group-III surfaces. For the systems Si(111) $\sqrt{3} \times \sqrt{3}$ :AlR 30°, Ga, and In, one surface state in the conduction band and two surface states in the valence band have been experimentally identified in close agreement with calculations.<sup>3,5,6</sup> The dispersion of the unoccupied surface state observed with KRIPES on the Si(111) $\sqrt{3} \times \sqrt{3}$ :AlR 30°, Ga, and In show a maximum in energy position at the  $\overline{\Gamma}$  point which is slightly different from the  $\Sigma_1$  band.

It has not yet been possible to produce a  $Si(111)\sqrt{3} \times \sqrt{3}$ :SiR 30° surface but information about the band structure on this surface can be gained from studies of the adatoms of the Si(111)7×7 surface. On the Si(111)7×7 surfaces three surface states  $S_1$ ,  $S_2$ , and  $S_3$  are identified below the Fermi level and one surface state  $U_1$  is found in the unoccupied region.<sup>17,15</sup> The  $S_3$  and the  $U_1$  states showed dispersions similar to the calculated  $\Sigma_3$  and  $\Sigma_1$  bands of the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° surface. It is suggested that the  $\Sigma_1$  state is empty and corresponds to the backbond state  $\Sigma_3$ .

Total energy calculations of different adatom geometries of the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface<sup>9,10</sup> show that a configuration with the B atom in the S-B<sub>5</sub> position is energetically the most favorable. In the B-S<sub>5</sub> configuration the Si atom in the adatom position forms three bonds to its nearest Si neighbors in the first layer and donates one electron to the B atom directly below it. As a result, the dangling bond of the adatom becomes unoccupied.

A comparison between the calculated dispersion of the empty dangling-bond state of the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface<sup>11</sup> and the U state, in Fig. 4, reveals similar bandwidths (0.6 and 0.65 eV, respectively), but different shapes around the  $\overline{\Gamma}$  and  $\overline{\Gamma}'$  points. Around those two points the calculated dispersion shows a maximum in energy position whereas the U state shows a minimum. The U state and the  $\Sigma_1$  band show different bandwidths (0.44 and 0.65 eV, respectively).

The origin of the local minima in the dispersion of Uobserved at the  $\overline{\Gamma}$  and  $\overline{\Gamma}'$  points, but not observed for the other Si(111) $\sqrt{3} \times \sqrt{3}$  systems, is not fully understood. In the S-B<sub>5</sub> model the adatom donates one electron to the second-layer B atom and it can be argued that the minima observed in the dispersion of the U band at the  $\overline{\Gamma}$ and  $\overline{\Gamma}'$  points are effects of surface relaxation, correlated to the charge transfer.

dispersion of the  $Si(111)\sqrt{3}$ The calculated  $\times \sqrt{3}$ :SiR 30° surface,<sup>16</sup> in the occupied region, is proposed to have an intensity maximum at the border of the  $1 \times 1$  SBZ that is at the  $\overline{M}'$  point in the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$  direction and at the  $\overline{\Gamma}'$  point in the  $\overline{\Gamma} \cdot \overline{M}'$  direction. Strong intensity of the  $\Sigma_3$  is indicated with a solid line in Fig. 4. The experimentally observed dispersions of the  $Si(111)\sqrt{3} \times \sqrt{3}$ -Al, Ga, and In systems follows, in general, the shape and intensity behavior of the calculated dispersions. The dispersion of the surface state  $A'_{3}$  of the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface (Fig. 4) in the  $\overline{\Gamma}$ - $\overline{K}'$ - $\overline{M}'$ direction resembles quite well the  $\Sigma_3$  band of the  $Si(111)\sqrt{3} \times \sqrt{3}$ :SiR 30° surface. The different energy values for the  $\overline{M}'$  points in the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$  and the  $\overline{\Gamma} \cdot \overline{M}'$ directions indicate, as mentioned above, that  $A_3$  and  $A'_3$ contain two occupied bands with different intensity to  $k_{\parallel}$ relation. The  $A_3$  band in the  $\overline{\Gamma} \cdot \overline{M}'$  direction does not follow the intensity profile of the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° surface, however. This can be an effect of the different periodicity in the two top layers of the  $S-B_5$  model as compared to the  $T_4$  model. In a surface where a B atom has occupied every  $Si-B_5$  position the periodicity of both the adatom and the second layer is  $\sqrt{3} \times \sqrt{3}$ , whereas when the group-III atoms\_occupy the  $T_4$  position only the adatoms have the  $\sqrt{3} \times \sqrt{3}$  periodicity. The  $A_4$ structure, which is only detected around the  $\overline{\Gamma}'$  point, is clearly positioned in the band gap of the projected bulk and must therefore originate from the surface. The existence of a state similar to the  $A_4$  has not been reported for any of the surfaces Si(111) $\sqrt{3} \times \sqrt{3}$ :AlR 30°, Ga, In, or the Si(111)7  $\times$  7.

After exposing the surface to 250 L H<sub>2</sub> in the presence of a hot filament the peak  $A_3$  decreases in intensity whereas the peak  $A_4$  is unaffected. The structure  $A_3$  which shows a dispersion similar to the  $\Sigma_3$  band of the Si(111) $\sqrt{3} \times \sqrt{3}$ :SiR 30° surface is suggested to originate from the backbond of the Si atom in the  $T_4$  position, i.e., a Si adatom in the position directly above a second-layer atom.

For the Si(111) $\sqrt{3} \times \sqrt{3}$ :group-III systems studied so far, the Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° is the only one where the metal atom is likely to be positioned below the top layer. The Si(111) $\sqrt{3} \times \sqrt{3}$ :BR 30° surface is the only surface for which the filled surface states are found to be separated at the  $\overline{\Gamma}'$  point. It is therefore suggested that the  $A_4$  state, observed only at the  $\overline{\Gamma}'$  point, in this case originates from the bonds between the B atom in the S-B<sub>5</sub> position and the surrounding Si atoms. The position of these bonds, below the surface, could explain the behavior of the  $A_4$ structure during the hydrogen exposure.

### SUMMARY

In summary, with k-resolved inverse photoemission one dispersing surface state is observed at 1.15 eV above the Fermi level at the  $\overline{\Gamma}$  point with a total bandwidth of 0.65 eV. In the occupied region, two overlapping surface states  $A_3$  and  $A'_3$  corresponding to the backbond between the adatom and the first-layer Si atoms, are observed. One surface state  $A_4$  found only in the vicinity of the  $\overline{\Gamma}'$  point is associated with the bonding between the B atom in the S-B<sub>5</sub> position and the surrounding Si atoms.

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- \*Permanent address: R&D Center, Sandvik Steel AB, S-81181 Sandviken, Sweden.
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FIG. 4. Plot of the surface-state dispersion for the directions  $\overline{\Gamma} \cdot \overline{M}'$  and the  $\overline{\Gamma} \cdot \overline{K}' \cdot \overline{M}'$ . Included in the figure are calculated surface-state dispersions for the reconstructions  $\mathrm{Si}(111)\sqrt{3} \times \sqrt{3} : \mathrm{SBR} 30^\circ$  (Ref. 11) (-----) and  $\mathrm{Si}(111)\sqrt{3} \times \sqrt{3} : \mathrm{Si}R 30^\circ$  (Ref. 15) (-----). The dispersion labeled  $- \cdot - \cdot - \cdot$  is measured by Kaxiras *et al.* (Ref. 11). The shaded areas represent the projected bulk ( $E_F - E_{\mathrm{VBM}} = 0.5 \text{ eV}$ ) (Ref. 14).